

# **1<sup>st</sup> Workshop on Dependability Issues in Deep-submicron Technologies**

## *Preliminary Program*

### **May 26<sup>th</sup>, 2011**

#### **16.45-17.15: Registration**

#### **17.15-17.30: Opening**

*Massimo Violante, workshop organizer*

#### **17.30-18.30: Keynote**

On the dependability of 3D interconnects

*M. Nicolaidis, L. Anghel, V. Pasca*

### **May 27<sup>th</sup>, 2011**

#### **08.30-09.00: Registration**

#### **09.00-11.00: Session 1**

On-line Software-Based Self-Test in Automotive Electronics: Problems and Solutions

*P. Bernardi, M. De Carvalho, M. Grosso, J. Lagos-Benites, E. Sanchez, O. Ballan*

Non-Intrusive Hybrid Signature-Based Technique to Detect SEEs in Microprocessors

*J. R. Azambuja, M. Altieri, M. Hübner, F. Lima Kastensmidt*

Study on the Level of Confidence for Roll-back Recovery with Checkpointing

*D. Nikolov, U. Ingelsson, V. Singh, E. Larsson*

Algorithm Transformation Methods to Reduce Software-only Fault Tolerance Techniques'Overhead

*J. Rodrigo Azambuja, G. Brown, F. Lima Kastensmidt, L. Carro*

#### **11.00-11.15: Coffee break**

#### **11.15-11.45: Session 2**

A Robust Infrastructure for Data Collection and Transfer for a Distributed SRAM-based Neutron Detection Platform

*L. Dilillo, A. Bosio, P. Girard, S. Pravossoudovitch, A. Virazel*

FT-Unshades2: On the Cutting Edge of Fault Injection Platforms for SEE Evaluation

*J.M. Mogollon, H. Guzmán-Miranda, J. Nápoles, J. Barrientos, M.A. Aguirre*

Does Placement Affect SEU Sensitivity of SRAM-based FPGAs?

*M. Alderighi, F. Casini, S. D'Angelo, A. Gravina, V. Liberali, M. Mancini, S. Pastore, G. Sorrenti*

#### **12.45-13.00: Closing**

#### **13.00-14.30: Lunch**